IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of: Fabrice LETERTRE et al.

Application No.:

Group Art Unit:

Filing Date:

Concurrently herewith

Examiner:

For:

WAFER AND METHOD OF PRODUCING A

SUBSTRATE BY TRANSFER OF A LAYER

THAT INCLUDES FOREIGN SPECIES

Attorney Docket No.: 4717-7400

INFORMATION DISCLOSURE STATEMENT

MS PATENT APPLICATION

Commissioner for Patents P.O. Box 1450 Arlexandria, Virginia 22313-1450

ober 6, 2003

Sir:

Pursuant to Applicant's duty of disclosure under 37 C.F.R. § 1.56, enclosed are copies of four (4) references listed on the enclosed Form PTO-1449 for the Examiner's review. Also enclosed is a copy of the International Search Report from the priority foreign application on which the references were cited. It is respectfully requested that the references be made of record in this application by the Examiner's completion and return of the attached Form PTO-1449.

No fee is believed to be due for the submission of the references. Should any fees be required, however, please charge such fees to Winston & Strawn Deposit Account No. 50-1814. A copy of this sheet is enclosed for accounting purposes.

Data

Respectfully submitted,

E. Bradley Gould

(Reg. No. 41,792)

For: Mlan A. Fanucci

(Reg. No. 30,256)

WINSTON & STRAWN Customer No. 28765

202-371-5771

LIST OF REFERENCES CITED BY APPLICANT Form PTO-1449 (Use several sheets if necessary)						ATTY. DOCKET NO.: 4717-7400 APPLICANT:			N NO.:		
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	C R. Fornari et al., "Homogeneity of thermally annealed Fe-doped InP wafers," 1997 D A. Näser et all., "Thermal stability of the midgap acceptor rhodium in indium phosphide" 1995										
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